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Applicant(s)

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J. Thiele et al. File, Date Group

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Exam.		Document			Class/	Filing
Intl.		Number	Date	Name	Subclass	Date
2	A1 :	5,025,430	06/18/91	Takokoro et al.	G 11B 13/04	03/31/88
α ,	: A2 :	5,530,685	06/25/96	Katayama et al.	G1 % B 11/00	10/28/94
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FOREIGN COUNTRIES

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B1						:	•
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: B5							
В6							
B7							
В8						•	
В9						•	•

OTHER PRIOR ART (INCLUDE AUTHOR, TITLE, DATE, PERTINENT PAGE,

- A. Partovi et al., High -Power Laser Light For Near-Field Optics and Its Application to High-Density Optical Data Storage, 09/13/99, Volume 75, Number 11, pages 1515-1517.
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EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

C3 C4 C5